Examiner-Initiated Interview Summary	Application No.	Applicant(s)
	10/591,116	THOMASSET, JACQUES
	Examiner	Art Unit
	ERIK KASHNIKOW	1794
Il Participants: Status of Application:		
(1) ERIK KASHNIKOW.	(3)	
(2) <u>Mr. Duane M. Byers</u> .	(4)	
Date of Interview: 21 January 2008	Time: <u>11:00 AM</u>	
Type of Interview:		
Part I.		
Rejection(s) discussed: n/a		
Claims discussed: 2		
Prior art documents discussed: n/a		
Part II.		
SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED: See Continuation Sheet		
Part III.		
<ul> <li>It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.</li> <li>It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above.</li> </ul>		
/Callie E. Shosho/ Supervisory Patent Examiner, Art Unit 1794	Applicant/Applicant's Representat	ive Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: Examiner called Mr. Byers to discuss an Examiner's Amendment. The result of the conversation was that Examiner and Mr. Byers agreed to amend claim 2, which originally read "[t]he object as claimed in claim 1 wherein a superposition distance is at least equal to the thickness E of the object". The claim will now read "[t]he object as claimed in claim 1 wherein an overlap of the at least two fine functional layers is at least equal to the thickness E of the object".